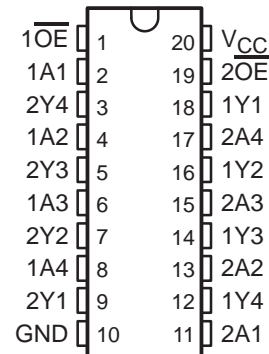


# SN54LVTH244A, SN74LVTH244A 3.3-V ABT OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

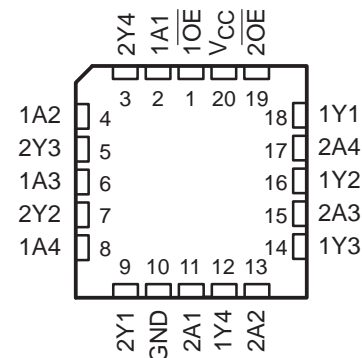
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- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power Dissipation
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V  $V_{CC}$ )
- Support Unregulated Battery Operation Down to 2.7 V
- Typical  $V_{OLP}$  (Output Ground Bounce)  $< 0.8$  V at  $V_{CC} = 3.3$  V,  $T_A = 25^\circ\text{C}$
- $I_{off}$  and Power-Up 3-State Support Hot Insertion
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ( $C = 200$  pF,  $R = 0$ )
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Packages, and Ceramic (J) DIPs

SN54LVTH244A . . . J OR W PACKAGE  
SN74LVTH244A . . . DB, DW, OR PW PACKAGE  
(TOP VIEW)



SN54LVTH244A . . . FK PACKAGE  
(TOP VIEW)



## description

These octal buffers and line drivers are designed specifically for low-voltage (3.3-V)  $V_{CC}$  operation, but with the capability to provide a TTL interface to a 5-V system environment.

The 'LVTH244A devices are organized as two 4-bit line drivers with separate output-enable ( $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the devices pass data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When  $V_{CC}$  is between 0 and 1.5 V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

These devices are fully specified for hot-insertion applications using  $I_{off}$  and power-up 3-state. The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.

The SN54LVTH244A is characterized for operation over the full military temperature range of  $-55^\circ\text{C}$  to  $125^\circ\text{C}$ . The SN74LVTH244A is characterized for operation from  $-40^\circ\text{C}$  to  $85^\circ\text{C}$ .



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

 **TEXAS  
INSTRUMENTS**

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On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

# SN54LVTH244A, SN74LVTH244A

## 3.3-V ABT OCTAL BUFFERS/DRIVERS

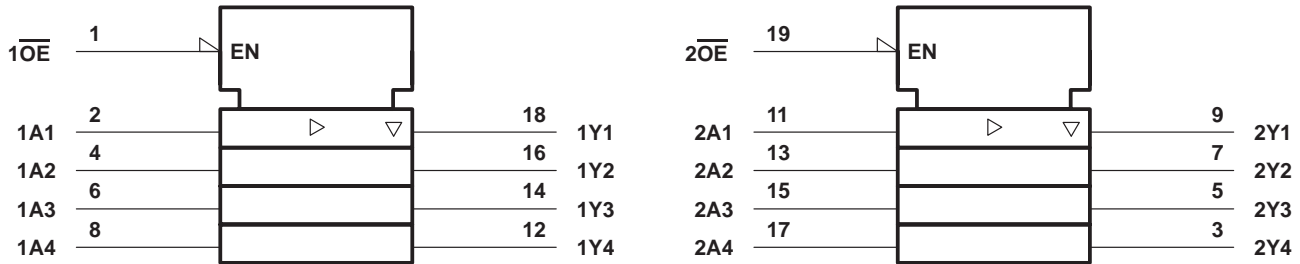
### WITH 3-STATE OUTPUTS

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FUNCTION TABLE  
(each buffer)

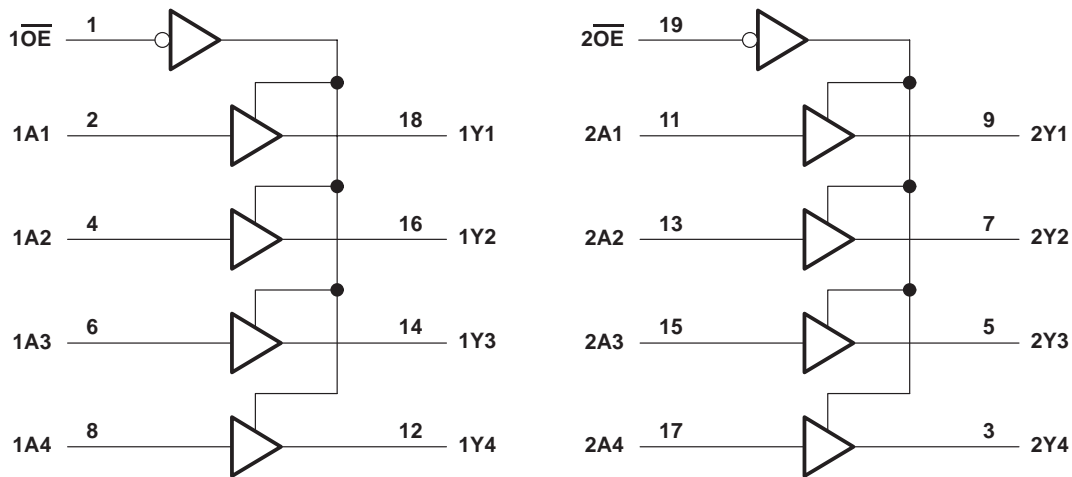
INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

#### logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)



# SN54LVTH244A, SN74LVTH244A 3.3-V ABT OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$ .....	–0.5 V to 4.6 V
Input voltage range, $V_I$ (see Note 1) .....	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance or power-off state, $V_O$ (see Note 1) .....	–0.5 V to 7 V
Voltage range applied to any output in the high state, $V_O$ (see Note 1) .....	–0.5 V to $V_{CC} + 0.5$ V
Current into any output in the low state, $I_O$ : SN54LVTH244A .....	96 mA
SN74LVTH244A .....	128 mA
Current into any output in the high state, $I_O$ (see Note 2): SN54LVTH244A .....	48 mA
SN74LVTH244A .....	64 mA
Input clamp current, $I_{IK}$ ( $V_I < 0$ ) .....	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ ) .....	–50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): DB package .....	115°C/W
DW package .....	97°C/W
PW package .....	128°C/W
Storage temperature range, $T_{stg}$ .....	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.  
 2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .  
 3. The package thermal impedance is calculated in accordance with JESD 51.

## recommended operating conditions (see Note 4)

		SN54LVTH244A		SN74LVTH244A		UNIT
		MIN	MAX	MIN	MAX	
$V_{CC}$	Supply voltage	2.7	3.6	2.7	3.6	V
$V_{IH}$	High-level input voltage	2		2		V
$V_{IL}$	Low-level input voltage		0.8		0.8	V
$V_I$	Input voltage		5.5		5.5	V
$I_{OH}$	High-level output current		–24		–32	mA
$I_{OL}$	Low-level output current		48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled			10	ns/V
$\Delta t/\Delta V_{CC}$	Power-up ramp rate	200		200		μs/V
$T_A$	Operating free-air temperature	–55	125	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



**SN54LVTH244A, SN74LVTH244A**  
**3.3-V ABT OCTAL BUFFERS/DRIVERS**  
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**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS		SN54LVTH244A			SN74LVTH244A			UNIT	
			MIN	TYP†	MAX	MIN	TYP†	MAX		
V <sub>IK</sub>	V <sub>CC</sub> = 2.7 V, I <sub>I</sub> = -18 mA		-1.2			-1.2			V	
V <sub>OH</sub>	V <sub>CC</sub> = 2.7 V to 3.6 V, I <sub>OH</sub> = -100 μA		V <sub>CC</sub> -0.2			V <sub>CC</sub> -0.2			V	
	V <sub>CC</sub> = 2.7 V, I <sub>OH</sub> = -8 mA		2.4			2.4				
	V <sub>CC</sub> = 3 V	I <sub>OH</sub> = -24 mA	2			2				
V <sub>OL</sub>	V <sub>CC</sub> = 2.7 V	I <sub>OL</sub> = 100 μA	0.2			0.2			V	
		I <sub>OL</sub> = 24 mA	0.5			0.5				
	V <sub>CC</sub> = 3 V	I <sub>OL</sub> = 16 mA	0.4			0.4				
		I <sub>OL</sub> = 32 mA	0.5			0.5				
		I <sub>OL</sub> = 48 mA	0.55			0.55				
I <sub>I</sub>	V <sub>CC</sub> = 0 or 3.6 V, V <sub>I</sub> = 5.5 V		50			10			μA	
	Control inputs	V <sub>CC</sub> = 3.6 V, V <sub>I</sub> = V <sub>CC</sub> or GND		±1			±1			
	Data inputs	V <sub>CC</sub> = 3.6 V		1			1			
V <sub>I</sub> = 0		-5			-5					
I <sub>off</sub>	V <sub>CC</sub> = 0, V <sub>I</sub> or V <sub>O</sub> = 0 to 4.5 V					±100			μA	
I <sub>I</sub> (hold)	Data inputs	V <sub>CC</sub> = 3 V	V <sub>I</sub> = 0.8 V	75			75			μA
		V <sub>CC</sub> = 3 V	V <sub>I</sub> = 2 V	-75			-75			
		V <sub>CC</sub> = 3.6 V‡, V <sub>I</sub> = 0 to 3.6 V				500 -750				
I <sub>OZH</sub>	V <sub>CC</sub> = 3.6 V, V <sub>O</sub> = 3 V		5			5			μA	
I <sub>OZL</sub>	V <sub>CC</sub> = 3.6 V, V <sub>O</sub> = 0.5 V		-5			-5			μA	
I <sub>OZPU</sub>	V <sub>CC</sub> = 0 to 1.5 V, V <sub>O</sub> = 0.5 V to 3 V, OE = don't care		±100*			±100			μA	
I <sub>OZPD</sub>	V <sub>CC</sub> = 1.5 V to 0, V <sub>O</sub> = 0.5 V to 3 V, OE = don't care		±100*			±100			μA	
I <sub>CC</sub>	V <sub>CC</sub> = 3.6 V, I <sub>O</sub> = 0, V <sub>I</sub> = V <sub>CC</sub> or GND	Outputs high	0.39			0.19			mA	
		Outputs low	14			5				
		Outputs disabled	0.39			0.19				
ΔI <sub>CC</sub> §	V <sub>CC</sub> = 3 V to 3.6 V, One input at V <sub>CC</sub> - 0.6 V, Other inputs at V <sub>CC</sub> or GND		0.2			0.2			mA	
C <sub>i</sub>	V <sub>I</sub> = 3 V or 0		3			3			pF	
C <sub>o</sub>	V <sub>O</sub> = 3 V or 0		7			7			pF	

\* On products compliant to MIL-PRF-38535, this parameter is not production tested.

† All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.



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**WITH 3-STATE OUTPUTS**

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switching characteristics over recommended operating free-air temperature range,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

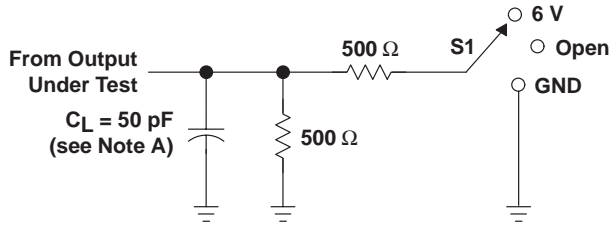
PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVTH244A				SN74LVTH244A				UNIT	
			$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$			$V_{CC} = 2.7\text{ V}$		
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN		MAX
$t_{PLH}$	A	Y	0.5	4.7	4.1		1.1	2.3	3.5	3.8		ns
$t_{PHL}$			0.5	4.4	3.9		1.3	2.1	3.3	3.6		
$t_{PZH}$	$\overline{OE}$	Y	0.8	6.9	6		1.1	2.5	4.5	5.3		ns
$t_{PZL}$			0.8	5.4	5.4		1.4	2.7	4.4	4.9		
$t_{PHZ}$	$\overline{OE}$	Y	1.3	6.2	5.8		1.9	2.8	4.4	4.5		ns
$t_{PLZ}$			1.2	5.5	4.8		1.8	2.9	4.4	4.4		

† All typical values are at  $V_{CC} = 3.3\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**SN54LVTH244A, SN74LVTH244A**  
**3.3-V ABT OCTAL BUFFERS/DRIVERS**  
**WITH 3-STATE OUTPUTS**

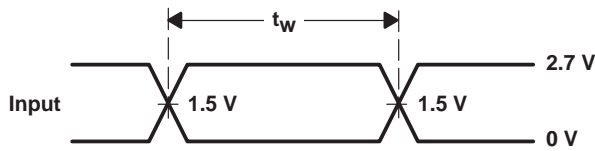
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**PARAMETER MEASUREMENT INFORMATION**

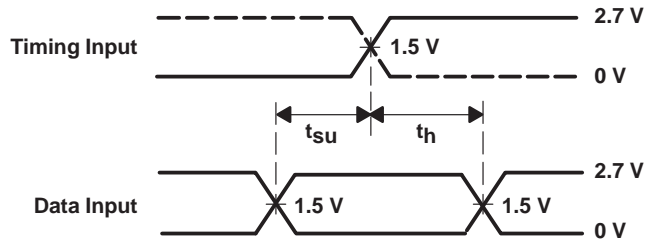


**LOAD CIRCUIT**

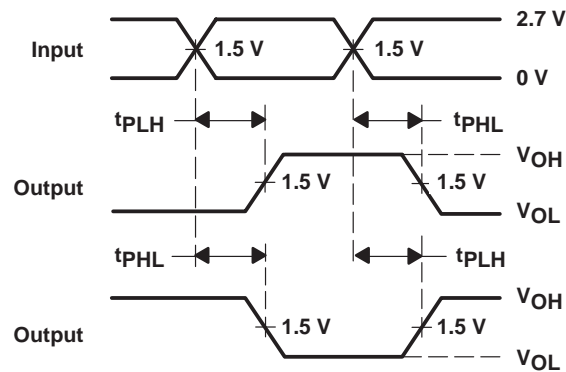
TEST	S1
$t_{PLH}/t_{PHL}$	Open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PZH}$	GND



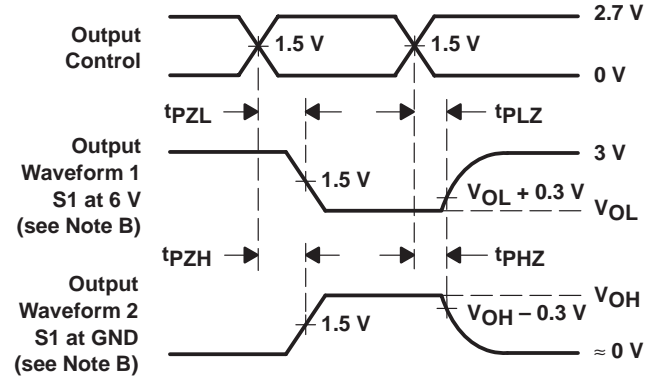
**VOLTAGE WAVEFORMS**  
**PULSE DURATION**



**VOLTAGE WAVEFORMS**  
**SETUP AND HOLD TIMES**



**VOLTAGE WAVEFORMS**  
**PROPAGATION DELAY TIMES**  
**INVERTING AND NONINVERTING OUTPUTS**



**VOLTAGE WAVEFORMS**  
**ENABLE AND DISABLE TIMES**  
**LOW- AND HIGH-LEVEL ENABLING**

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5 \text{ ns}$ ,  $t_f \leq 2.5 \text{ ns}$ .  
 D. The outputs are measured one at a time with one transition per measurement.

**Figure 1. Load Circuit and Voltage Waveforms**

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